

Notice of References Cited	Application/Control No. 09/824,301	Applicant(s)/Patent Under Reexamination BODE ET AL.	
	Examiner Sean P. Shechtman	Art Unit 2125	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,546,312 /	08-1996	Mozumder et al.	364/468.03
	B	US-2002/0147960 A1 /	10-2002	Jevtic et al.	716/19
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Karzhavin, "Advanced Process Control Project at Infineon Technologies, Richmond" February 2 nd 2002, Future Fab Intl. Vol. 12, page 12. /
	V	Marsden, "Automatic Data Collection Baseline Requirements: Levels 1 and 2 Events and Variables" October 31 st 2000, Technology Transfer # 00094004A-ENG, International SEMATECH Inc., pages 2 and 20. /
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.